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HEARING AID COMPATIBILITY

Applicant Name:
Samsung Electronics Co., Ltd.
129, Samsung-ro, Maetan dong,
Yeongtong-gu, Suwon-si
Gyeonggi-do 16677, Korea

Date of Testing:
07/04/2018 - 07/05/2018
Test Site/Location:
PCTEST Lab, Columbia, MD, USA
Test Report Serial No.:
1M1806290138-04.A3L

FCC ID:	**A3LSMN960U**
APPLICANT:	**SAMSUNG ELECTRONICS CO., LTD.**

Scope of Test:	Audio Band Magnetic Testing (T-Coil)
Application Type:	Class II Permissive Change
FCC Rule Part(s):	CFR §20.19(b)
HAC Standard:	ANSI C63.19-2011 CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017 285076 D01 HAC Guidance v05 285076 D02 T-Coil testing for CMRS IP v03
DUT Type:	Portable Handset
Model:	SM-N960U
Additional Model(s):	SM-N960U1, SM-N960W
Test Device Serial No.:	*Pre-Production Sample* [S/N: 44867]
Class II Permissive Change(s):	See FCC Change Document

C63.19-2011 HAC Category: T4 (SIGNAL TO NOISE CATEGORY, LTE B30/B38 only)

This report and category pertains only to the LTE bands 30 and 38 supported by this wireless portable device. The overall category rating of the device is determined by the lowest rating obtained over all air interfaces supported by the device. This wireless portable device has been shown to be hearing-aid compatible for LTE bands 30 and 38, under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez
President

ctia Authorized™ Test Lab
Lab Code: 20020221-00

ilac-MRA
ACCREDITED
TESTING CERT#2041.01

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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658[1] to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.

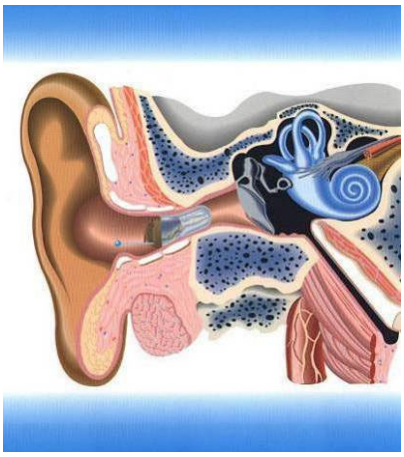

Figure 1-1 Hearing Aid *in-vitu*

[1] FCC Rule & Order, WT Docket 01-309 RM-8658

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2. DUT DESCRIPTION

FCC ID:	A3LSMN960U
Applicant:	Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea
Model(s):	SM-N960U
Additional Model(s):	SM-N960U1, SM-N960W
Serial Number:	44867
HW Version:	Rev.1.0
SW Version:	N960USQU0ARDF
Antenna:	Internal Antenna
DUT Type:	Portable Handset

Table 2-1
SM-N960U & SM-N960U1 HAC Air Interfaces

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service
CDMA	835	VO	No[1]	Yes: WIFI or BT	CMRS Voice*
	1900				
	EvDO	VD	No[1]	Yes: WIFI or BT	Google Duo**
GSM	850	VO	No[1]	Yes: WIFI or BT	CMRS Voice*
	1900				
	GPRS/EDGE	VD	No[1]	Yes: WIFI or BT	Google Duo**
UMTS	850	VD	No[1]	Yes: WIFI or BT	CMRS Voice*
	1700				
	1900				
	HSPA	VD	No[1]	Yes: WIFI or BT	Google Duo**
LTE (FDD)	680 (B71)	VD	No[1]	Yes: WIFI or BT	VoLTE*, Google Duo**
	700 (B12)				
	700 (B17)				
	780 (B13)				
	790 (B14)				
	850 (B5)				
	850 (B26)				
	1700 (B4)				
	1700 (B66)				
	1900 (B2)				
	1900 (B25)				
	2300 (B30)		Yes		
	2500 (B7)		No[1]		
LTE (TDD)	2600 (B38)	VD	Yes	Yes: WIFI or BT	VoLTE*, Google Duo**
	2600 (B41)		No[1]		
WIFI	2450	VD	No[1]	Yes: CDMA, GSM, UMTS, or LTE	VoWIFI**, Google Duo**
	5200 (U-NII 1)				
	5300 (U-NII 2A)				
	5500 (U-NII 2C)				
	5800 (U-NII 3)				
BT	2450	DT	No	Yes: CDMA, GSM, UMTS, or LTE	N/A

Type Transport
VO = Voice Only
DT = Digital Data - Not intended for CMRS Service
VD = CMRS and IP Voice over Data Transport

Notes:
* Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE Interpretation.
** Reference level is -20dBm0 in accordance with FCC KDB 285076 D02
1. This report pertains only to LTE bands 30 and 38. For full data, please refer to the Original Certification Test Report (T-Coil Test Report S/N: 1M1804270086-13-R1.A3L)

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Table 2-2
SM-N960W HAC Air Interfaces

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service
CDMA	835	VO	No[1]	Yes: WIFI or BT	CMRS Voice*
GSM	850	VO	No[1]	Yes: WIFI or BT	CMRS Voice*
	1900				
	GPRS/EDGE	VD	No[1]	Yes: WIFI or BT	Google Duo**
UMTS	850	VD	No[1]	Yes: WIFI or BT	CMRS Voice*
	1700				
	1900				
	HSPA	VD	No[1]	Yes: WIFI or BT	Google Duo**
LTE (FDD)	700 (B12)	VD	No[1]	Yes: WIFI or BT	VoLTE*, Google Duo**
	700 (B17)				
	780 (B13)				
	850 (B5)				
	1700 (B4)				
	1700 (B66)				
	1900 (B2)				
	1900 (B25)				
	2300 (B30)		Yes		
	2500 (B7)		No[1]		
LTE (TDD)	2600 (B41)	VD	No[1]	Yes: WIFI or BT	VoLTE*, Google Duo**
WIFI	2450	VD	No[1]	Yes: CDMA, GSM, UMTS, or LTE	VoWIFI**, Google Duo**
	5200 (U-NII 1)				
	5300 (U-NII 2A)				
	5500 (U-NII 2C)				
	5800 (U-NII 3)				
BT	2450	DT	No	Yes: CDMA, GSM, UMTS, or LTE	N/A

Type Transport
VO = Voice Only
DT = Digital Data - Not intended for CMRS Service
VD = CMRS and IP Voice over Data Transport

Notes:
* Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE Interpretation.
** Reference level is -20dBm0 in accordance with FCC KDB 285076 D02
1. This report pertains only to LTE bands 30 and 38. For full data, please refer to the Original Certification Test Report (T-Coil Test Report S/N: 1M1804270086-13-R1.A3L)

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3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

I. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be ≥ -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per §8.3.2.

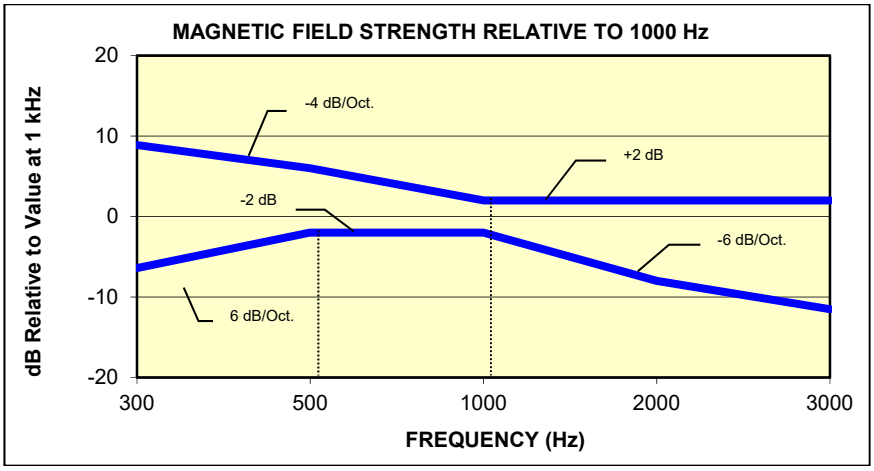

Figure 3-1
Magnetic field frequency response for Wireless Devices with an axial field ≤-15 dB(A/m) at 1 kHz

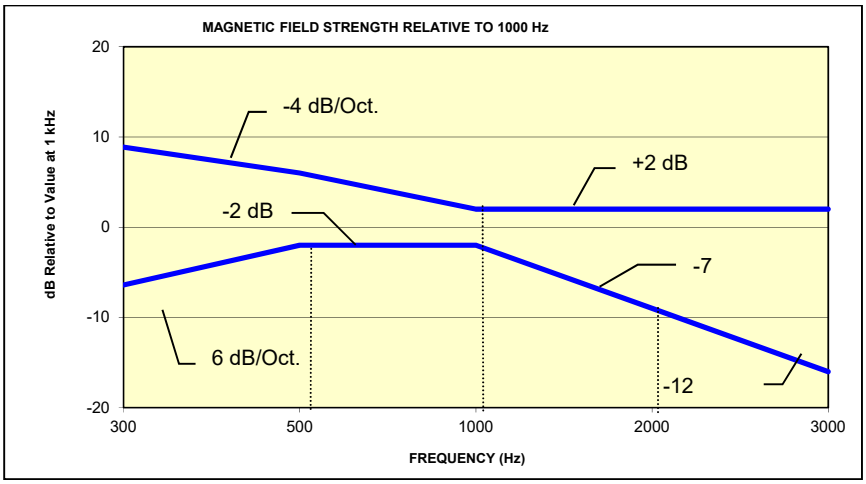

Figure 3-2
Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

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Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters
	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]
T1	0 to 10 dB
T2	10 to 20 dB
T3	20 to 30 dB
T4	> 30 dB

Table 3-1
Magnetic Coupling Parameters

Note: The FCC limit for SNNR is 20dB and the test data margins will indicate a margin from the FCC limit for compliance.

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4. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

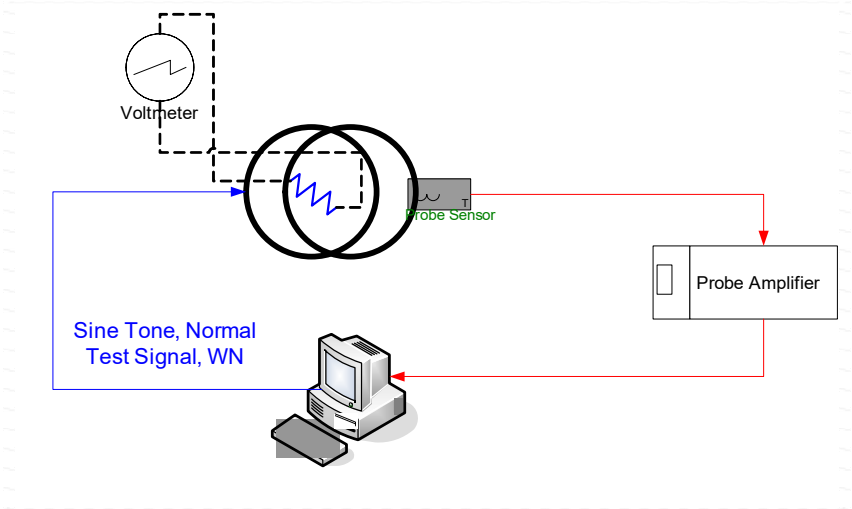

Figure 4-1
Validation Setup with Helmholtz Coil

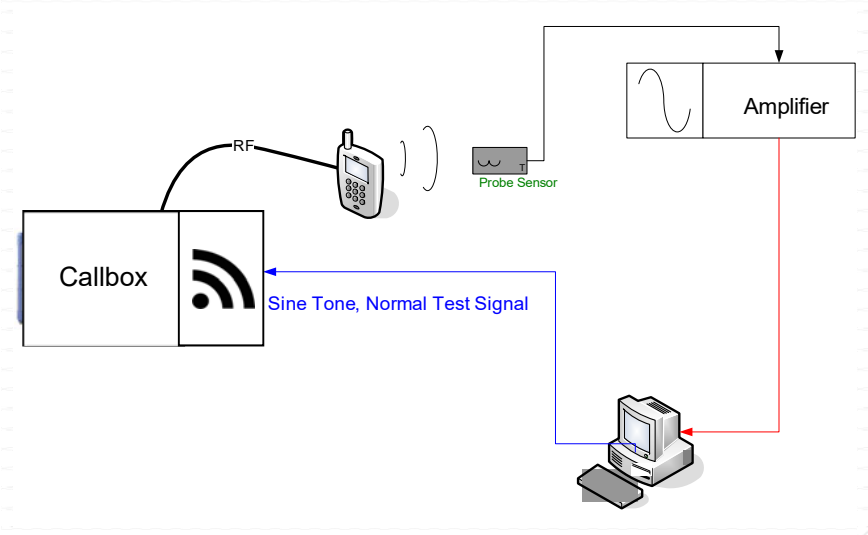

Figure 4-2
T-Coil Test Setup

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II. Scanning Mechanism

Manufacturer:	TEM
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36” x 25” x 38”
Operating Area:	36” x 49” x 55”
Reflections:	< -20 dB (in anechoic chamber)

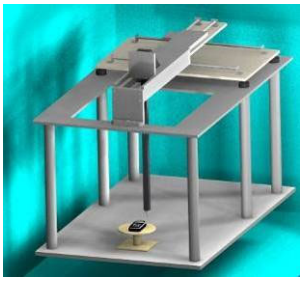

Figure 4-3
RF Near-Field Scanner

III. 3GPP2 Normal Test Signal (Speech)

Manufacturer:	3GPP2 (TIA 1042 §3.3.1)
Stimulus Type:	Modified-IRS weighted, multi-talker speech signal, 4 Male and 4 Female speakers (alternating)
Single Sample Duration:	51.62 seconds
Activity Level:	77.4%

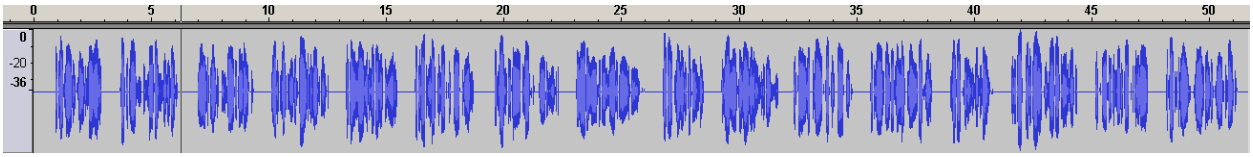

Figure 4-4
Temporal Characteristic of Normal Test Signal

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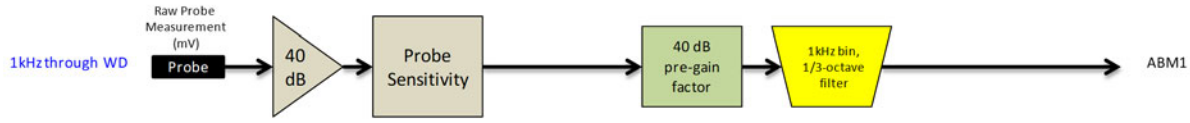
ABM1 Measurement Block Diagram:



ABM2 Measurement Block Diagram:

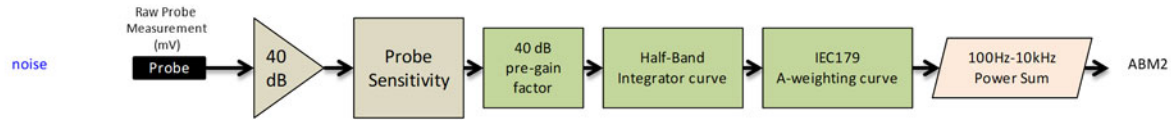


Figure 4-5 Magnetic Measurement Processing Steps

IV. Test Procedure

1. Ambient Noise Check per C63.19 §7.3.1
   a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
   b. "A-weighting" and Half-Band Integration was applied to the measurements.
   c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

      -18 - 30 - 10= -58 dBA/m
2. Measurement System Validation(See Figure 4-1)
   a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
   b. ABM1 Validation

      The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^3}}$$

Where H_c = magnetic field strength in amperes per meter
N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.08m; R=10.2Ω and using V=18mV:

$$H_c = \frac{20 \cdot (\frac{0.018}{10.2})}{0.08 \cdot \sqrt{1.25^3}} = 0.316 A/m \approx -10 dB(A/m)$$

Therefore a pure tone of 1kHz was applied into the coils such that 18mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10dB(A/m). This was verified to be within ± 0.5 dB of the -10dB(A/m) value (see Page 19).

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c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1kHz, between 300 – 3000 Hz using the Normal signal as shown below:

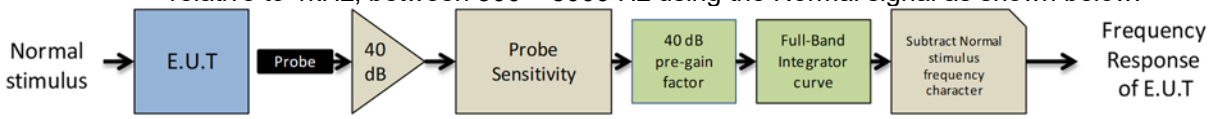

Figure 4-6 Frequency Response Validation

d. ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 4-1
ABM2 Frequency Response Validation

f (Hz)	HBI, A - Measured (dB re 1kHz)	HBI, A - Theoretical (dB re 1kHz)	dB Var.
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

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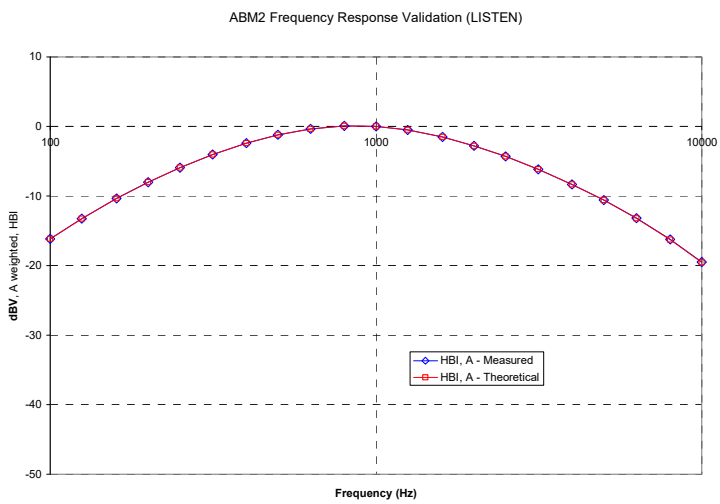

Figure 4-7
ABM2 Frequency Response Validation

The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-8). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:

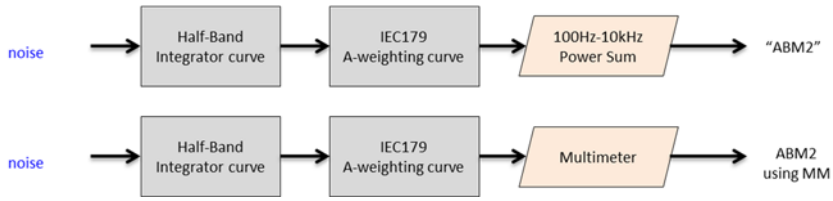

Figure 4-8
ABM2 Validation Block Diagram

The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 4-2
ABM2 Power Sum Validation

WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

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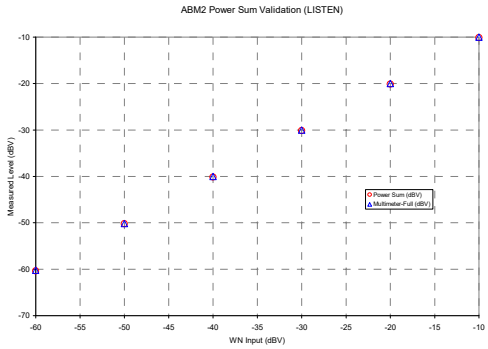

Figure 4-9
ABM2 Power Sum Validation

3. Measurement Test Setup
   a. Fine scan above the WD (TEM)
      i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-11, the grid is not to scale but merely a graphical representation of the coordinate system in use):

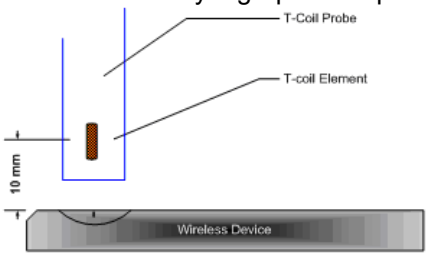

Figure 4-10
Measurement Distance

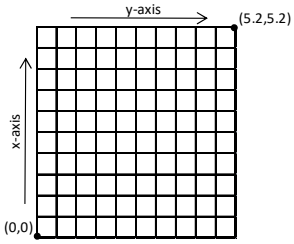

Figure 4-11
Measurement Grid

      ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
      iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-13 after a T-coil orientation was fully measured with the SoundCheck system.

   b. Speech Signal Setup to Base Station Simulator
      i. C63.19 Table 7-1 states audio reference input levels for various technologies:

Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16

   c. Real-Time Analyzer (RTA)
      i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
   d. WD Radio Configuration Selection
      i. The device was chosen to be tested in the worst-case ABM2 condition.

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4. Signal Quality Data Analysis
    a. Narrow-band Magnetic Intensity
        i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
    b. Frequency Response
        i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 – 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
        ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-6. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
        iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
    c. Signal Quality Index
        i. Ensuring the WD was at maximum RF power, maximum volume, backlight off, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz – 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
        ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
        iii. This result was subtracted from the ABM1 result in step 4.a, to obtain the Signal Quality.

V. Test Setup

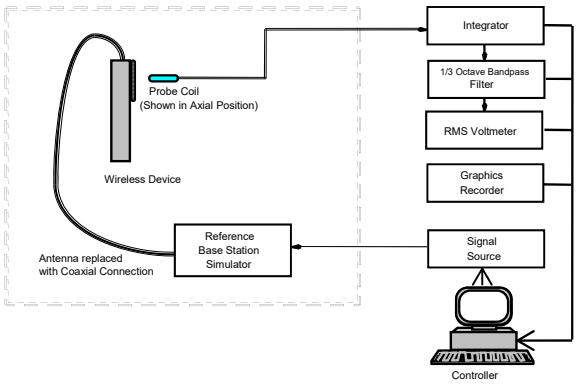

Figure 4-12
Audio Magnetic Field Test Setup

VI. Deviation from C63.19 Test Procedure

Non-conducted RF connection due to inaccessible RF ports.

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VII. Test Flow

The flow diagram below was followed (From C63.19):

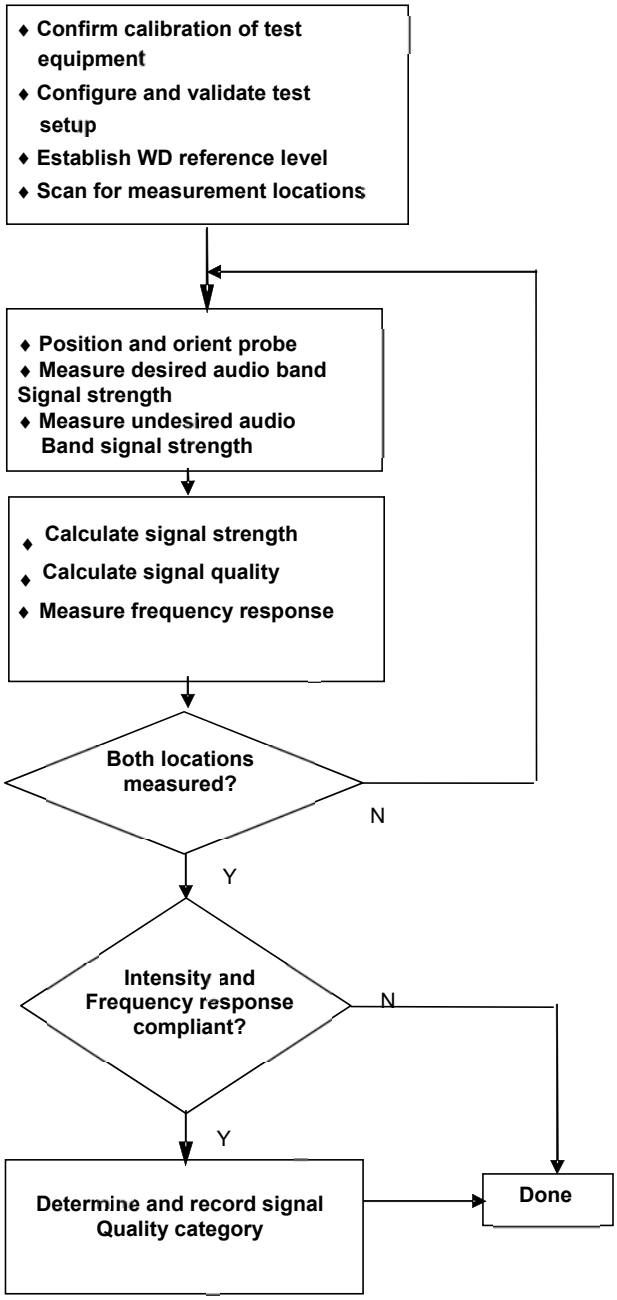

Figure 4-13
C63.19 T-Coil Signal Test Process

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5. TEST SUMMARY

Table 5-1
Consolidated Tabled Results

		Freq. Response Margin		Magnetic Intensity Verdict		FCC SNNR Verdict		Margin from FCC Limit (dB)	C63.19-2011 Rating
C63.19 Section		8.3.2		8.3.1		8.3.4			
		Axial	Radial	Axial	Radial	Axial	Radial		
LTE FDD	B30	PASS	NA	PASS	PASS	PASS	PASS	-21.60	T4
LTE FDD (OTT VoIP)	B30	PASS	NA	PASS	PASS	PASS	PASS	-30.74	T4
LTE TDD	B38	PASS	NA	PASS	PASS	PASS	PASS	-13.09	T4
LTE TDD (OTT VoIP)	B38	PASS	NA	PASS	PASS	PASS	PASS	-25.14	T4

I. Raw Handset Data

Table 5-2
Raw Data Results for LTE B30

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
LTE Band 30	Axial	10MHz	27710	0.88	-50.50	-59.85	2.00	51.38	20.00	-31.38	T4	2.2, 2.6
		5MHz	27710	0.84	-50.64		2.00	51.48	20.00	-31.48	T4	
	Radial	10MHz	27710	-6.04	-47.64	-63.84	N/A	41.60	20.00	-21.60	T4	2.2, 1.6
		5MHz	27710	-6.05	-48.04			41.99	20.00	-21.99	T4	

Table 5-3
Raw Data Results for LTE B38

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
LTE Band 38	Axial	20MHz	38000	1.23	-46.01	-59.85	1.98	47.24	20.00	-27.24	T4	2.2, 2.6
		15MHz	38175	1.15	-44.92		2.00	46.07	20.00	-26.07	T4	
		15MHz	38000	1.18	-45.10		2.00	46.28	20.00	-26.28	T4	
		15MHz	37825	1.04	-44.77		2.00	45.81	20.00	-25.81	T4	
		10MHz	38000	1.07	-45.68		2.00	46.75	20.00	-26.75	T4	
		5MHz	38000	0.91	-45.77		2.00	46.68	20.00	-26.68	T4	
	Radial	20MHz	38000	-5.79	-41.86	-63.84	N/A	36.07	20.00	-16.07	T4	2.2, 1.6
		15MHz	38175	-6.20	-41.61			35.41	20.00	-15.41	T4	
		15MHz	38000	-6.05	-41.38			35.33	20.00	-15.33	T4	
		15MHz	37825	-5.96	-39.05			33.09	20.00	-13.09	T4	
		10MHz	38000	-5.83	-41.95			36.12	20.00	-16.12	T4	
		5MHz	38000	-6.12	-42.39			36.27	20.00	-16.27	T4	

Table 5-4
Raw Data Results for LTE B30 (OTT VoIP)

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
LTE Band 30	Axial	10MHz	27710	9.66	-51.76	-59.85	2.00	61.42	20.00	-41.42	T4	2.2, 2.6
		5MHz	27735	9.64	-50.92		2.00	60.56	20.00	-40.56	T4	
		5MHz	27710	9.69	-51.22		2.00	60.91	20.00	-40.91	T4	
		5MHz	27685	9.52	-51.99		2.00	61.51	20.00	-41.51	T4	
	Radial	10MHz	27710	2.44	-48.30	-63.84	N/A	50.74	20.00	-30.74	T4	2.2, 1.6
		5MHz	27710	2.74	-48.35			51.09	20.00	-31.09	T4	

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04/17/2018

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Table 5-5
Raw Data Results for LTE B38 (OTT VoIP)

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
LTE Band 38	Axial	20MHz	38000	10.07	-46.81	-59.85	2.00	56.88	20.00	-36.88	T4	2.2, 2.6
		15MHz	38175	9.86	-46.41		2.00	56.27	20.00	-36.27	T4	
		15MHz	38000	9.55	-46.71		2.00	56.26	20.00	-36.26	T4	
		15MHz	37825	9.58	-46.06		2.00	55.64	20.00	-35.64	T4	
		10MHz	38000	9.77	-47.08		2.00	56.85	20.00	-36.85	T4	
		5MHz	38000	9.60	-46.92		2.00	56.52	20.00	-36.52	T4	
	Radial	20MHz	38000	2.95	-42.27	-63.84	N/A	45.22	20.00	-25.22	T4	2.2, 1.6
		15MHz	38175	2.95	-42.43			45.38	20.00	-25.38	T4	
		15MHz	38000	2.93	-42.21			45.14	20.00	-25.14	T4	
		15MHz	37825	2.94	-42.48			45.42	20.00	-25.42	T4	
		10MHz	38000	2.93	-42.34			45.27	20.00	-25.27	T4	
		5MHz	38000	2.93	-42.69			45.62	20.00	-25.62	T4	

II. Test Notes

A. General
1. Phone Condition: Mute on; Backlight off; Max Volume; Max Contrast
2. 'Radial' orientation refers to radial transverse.
3. Hearing Aid Mode (**Phone→Settings→More Settings→Hearing aids**) was set to ON for Frequency Response compliance
4. Speech Signal: 3GPP2 Normal Test Signal
5. Bluetooth and WIFI were disabled for 4G modes while testing.
6. The Margin from FCC limit column indicates a margin from the FCC limit for compliance (T4).
7. For each tested air interface mode, the test configuration was determined by the worst-case configuration in the Original Certification Test Report (T-Coil Test Report SN: 1M1804270086-13-R1.A3L). Please see that test report for more information on the chosen configuration.

B. LTE FDD
1. Power Configuration: TPC = “Max Power”
2. Radio Configuration: 16QAM, 1RB, 0RB offset
3. Vocoder Configuration: WB AMR 6.60kbps
4. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. LTE Band 30 at 10MHz is the worst-case for both Axial and Radial probe orientations, but only supports one channel. Therefore, no additional testing was performed.

C. LTE TDD
1. Power Configuration: TPC = “Max Power”
2. Radio Configuration: 16QAM, 1RB, 0RB offset
3. Uplink-Downlink configuration: 1
4. Vocoder Configuration: WB AMR 6.60kbps
5. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. LTE Band 38 at 15MHz is the worst-case for both Axial and Radial probe orientations.

D. OTT VoIP
1. Vocoder Configuration: 64kbps
2. LTE FDD Configuration:
   a. Power Configuration: TPC = “Max Power”
   b. Radio Configuration: 16QAM, 1RB, 0RB offset

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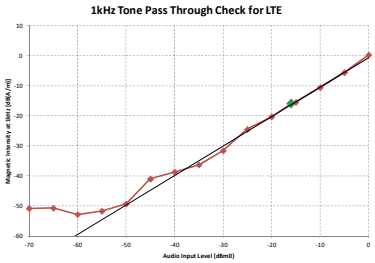
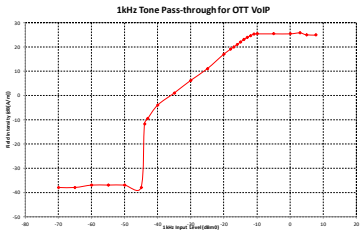
c. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. LTE Band 30 at 5MHz is the worst-case for the Axial probe orientation. LTE Band 30 at 10MHz is the worst-case for the Radial probe orientation, but only supports one channel. Therefore, no additional Radial testing was performed.

3. LTE TDD Configuration:
   a. Power Configuration: TPC = “Max Power”
   b. Radio Configuration: 16QAM, 1RB, 0RB offset
   c. Uplink-Downlink configuration: 1
   d. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. LTE Band 38 at 15MHz is the worst-case for both Axial and Radial probe orientations.

III. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -16 dBm0 for VoLTE over IMS. This measurement was taken in the axial configuration above the maximum location.



This model was verified to be within the linear region for ABM1 measurements at -20 dBm0 for OTT VoIP. This measurement was taken in the axial configuration above the maximum location.

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IV. T-Coil Validation Test Results

Table 5-6
Helmholtz Coil Validation Table of Results

Item	Target	Result	Verdict
Axial			
Magnetic Intensity, -10 dBA/m	*-10 ± 0.5 dB*	-10.172	**PASS**
Environmental Noise	< -58 dBA/m	-59.85	**PASS**
Frequency Response, from limits	*> 0 dB*	0.60	**PASS**
Radial			
Magnetic Intensity, -10 dBA/m	*-10 ± 0.5 dB*	-10.263	**PASS**
Environmental Noise	< -58 dBA/m	-63.84	**PASS**
Frequency Response, from limits	*> 0 dB*	0.70	**PASS**

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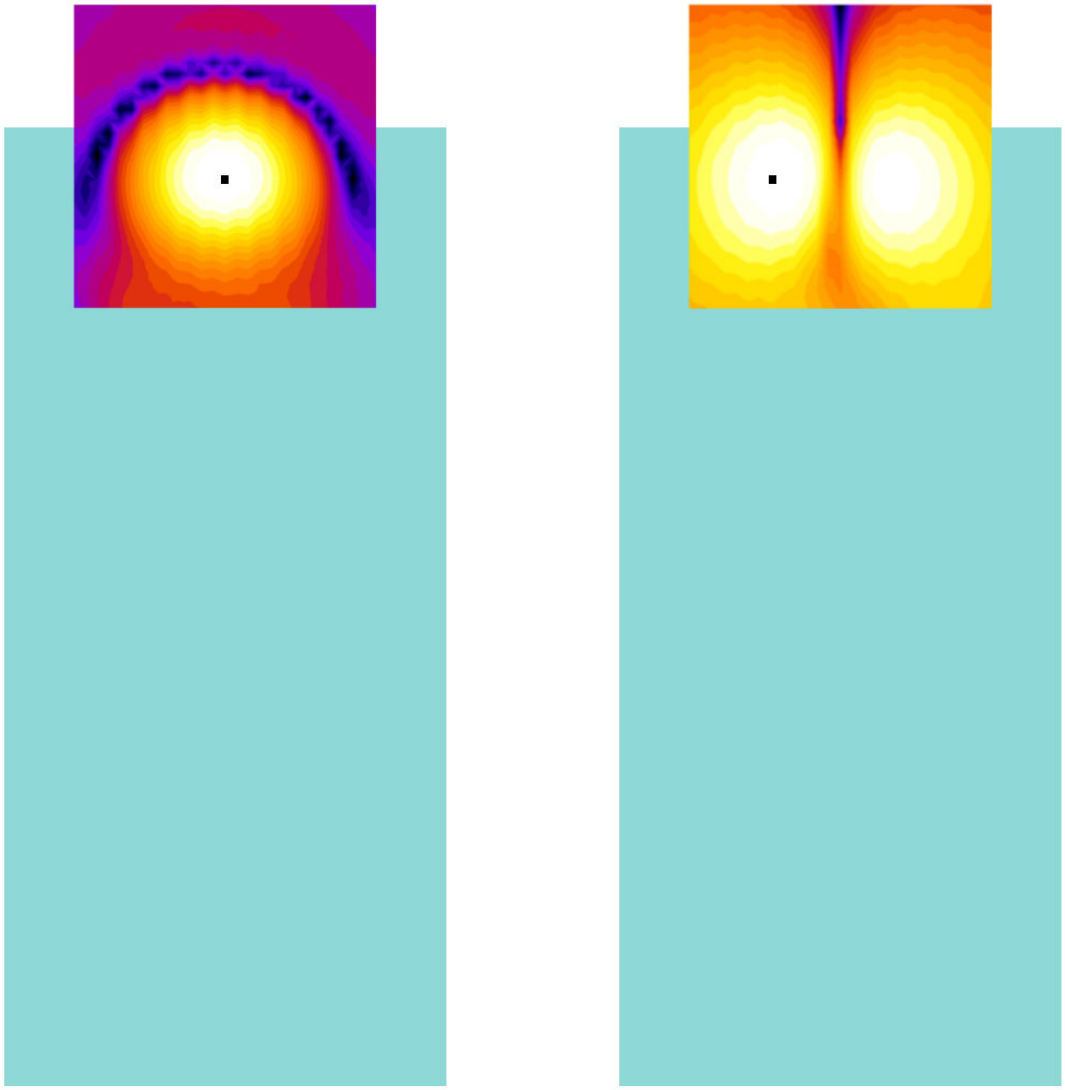
V. ABM1 Magnetic Field Distribution Scan Overlays



Axial Radial (Transverse)

Figure 5-1
T-Coil Scan Overlay Magnetic Field Distributions

Notes:
1. Final measurement locations are indicated by a cursor on the contour plots.
2. See Test Setup Photographs for actual WD overlay.

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6. MEASUREMENT UNCERTAINTY

Table 6-1
Uncertainty Estimation Table

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty, uc (k=1)						17.7%	0.71
Expanded uncertainty (k=2), 95% confidence level						35.3%	1.31

Notes:
1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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7. EQUIPMENT LIST

Table 7-1
Equipment List

Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Latitude E6540	SoundCheck Acoustic Analyzer Laptop	4/11/2017	Biennial	4/11/2019	7BFNM32
SoundConnect	Microphone Power Supply	N/A		N/A	0899-PS150
SoundConnect	Microphone Power Supply	12/2/2016	Biennial	12/2/2018	PS2612
Fireface UC	Soundcheck Acoustic Analyzer External Audio Interface	4/11/2017	Biennial	4/11/2019	23528889
CMW500	Wideband Radio Communication Tester	1/19/2018	Annual	1/19/2019	162125
NC-100	Torque Wrench (8" lb)	9/1/2016	Biennial	9/1/2018	21053
C63.19	Helmholtz Coil	12/7/2016	Biennial	12/7/2018	925
Radial T-Coil Probe	Radial T-Coil Probe	12/7/2016	Biennial	12/7/2018	TEM-1130
Axial T-Coil Probe	Axial T-Coil Probe	12/7/2016	Biennial	12/7/2018	TEM-1124
	HAC System Controller with Software	N/A		N/A	N/A
	HAC Positioner	N/A		N/A	N/A

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8. TEST DATA

See following attached pages for Test Data.

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07/04/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: HH Coil – SN: 925

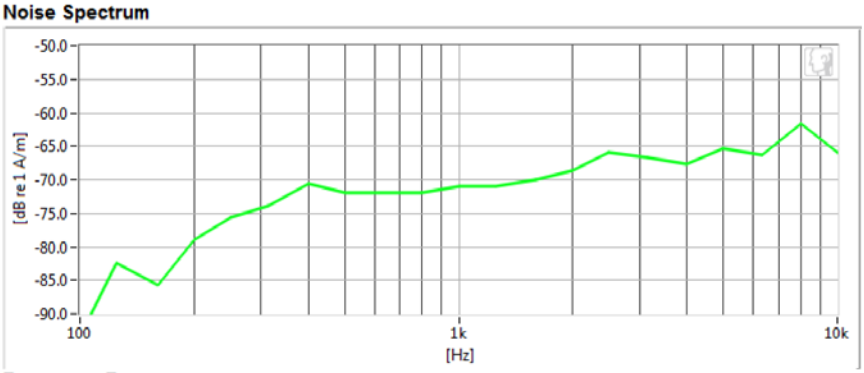
Type: HH Coil
Serial: 925

Measurement Standard: ANSI C63.19-2011

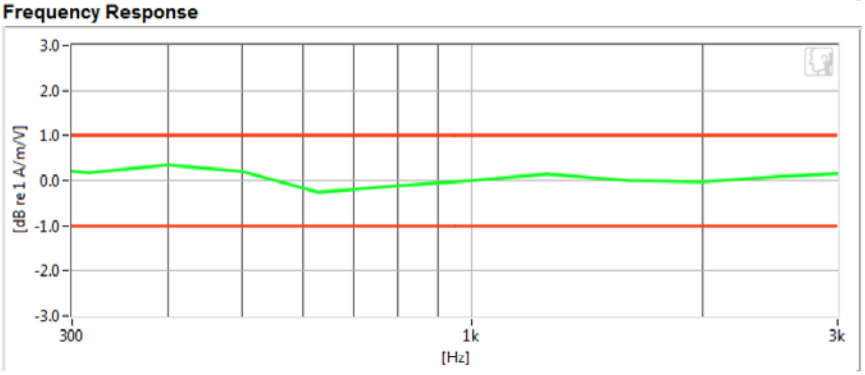
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016
- Helmholtz Coil – SN: 925; Calibrated: 12/07/2016

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-10.172	dB	✓	Max/Min	-9.5/-10.5
Verification ABM2	-59.85	dB	✓	Maximum	-58.0
Frequency Response Margin	600m	dB	✓	Tolerance curves	Aligned Data

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07/04/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: HH Coil – SN: 925

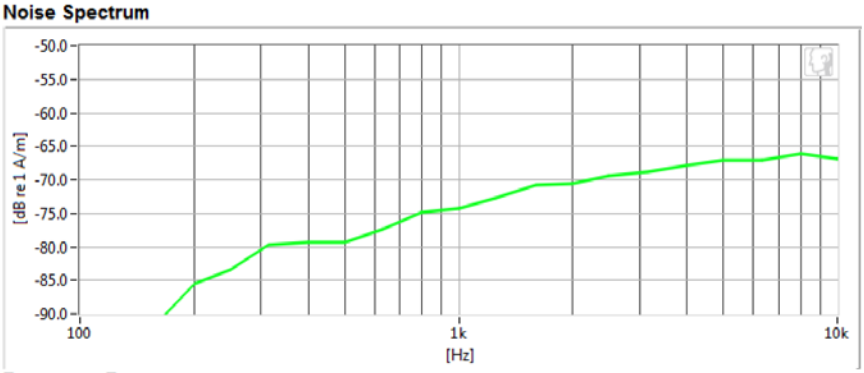
Type: HH Coil
Serial: 925

Measurement Standard: ANSI C63.19-2011

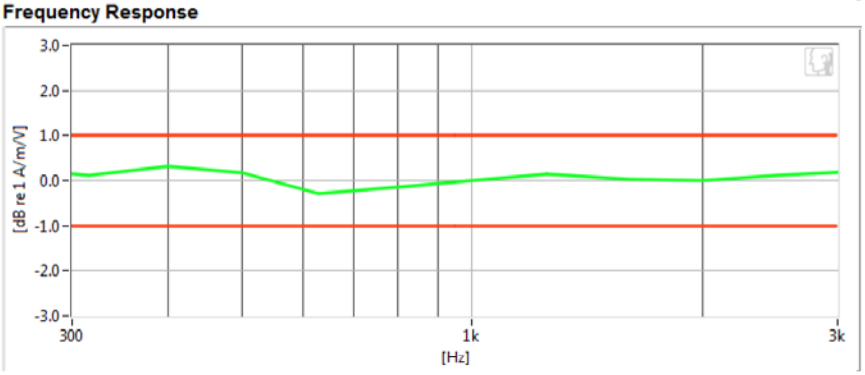
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016
- Helmholtz Coil – SN: 925; Calibrated: 12/07/2016

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-10.263 dB	✓	Max/Min	-9.5/-10.5
Verification ABM2	-63.84 dB	✓	Maximum	-58.0
Frequency Response Margin	700m dB	✓	Tolerance curves	Aligned Data

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07/04/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMN960U

Type: Portable Handset
Serial: 44867

Measurement Standard: ANSI C63.19-2011 / CTIA HAC Test Plan v3.1

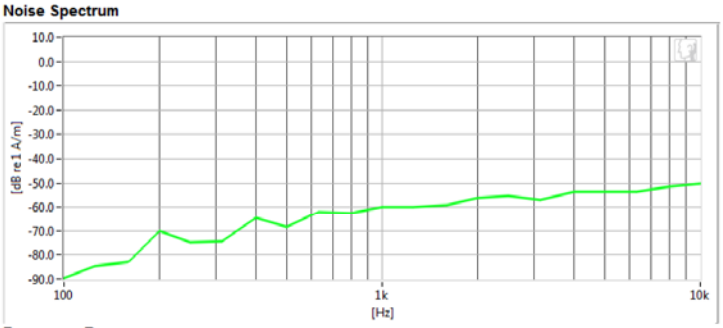
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

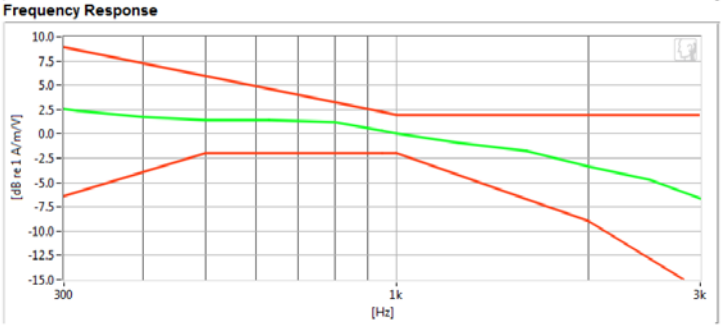
Test Configuration:

- Mode: LTE FDD Band 30
- Bandwidth: 10MHz
- Channel: 27710
- Speech Signal: 3GPP2 Normal Test Signal

Noise Spectrum



Frequency Response



Results

ABM1	880m dB	✓	Minimum	-18.0
ABM2	-50.5 dB	✓	Maximum	0.0
SNNR	51.38 dB	✓	Minimum	20.0
Aligned Response - Normal	2 dB	✓	Tolerance curves	Aligned Data

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07/04/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMN960U

Type: Portable Handset
Serial: 44867

Measurement Standard: ANSI C63.19-2011 / CTIA HAC Test Plan v3.1

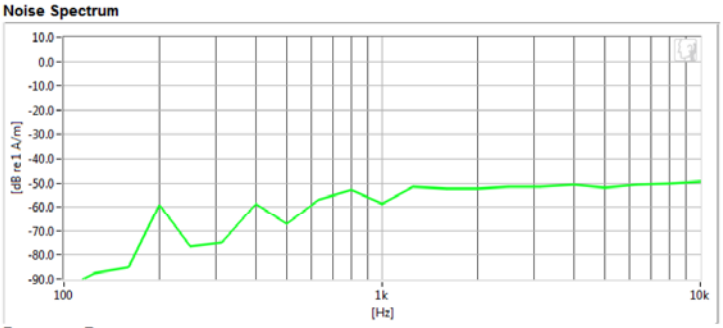
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

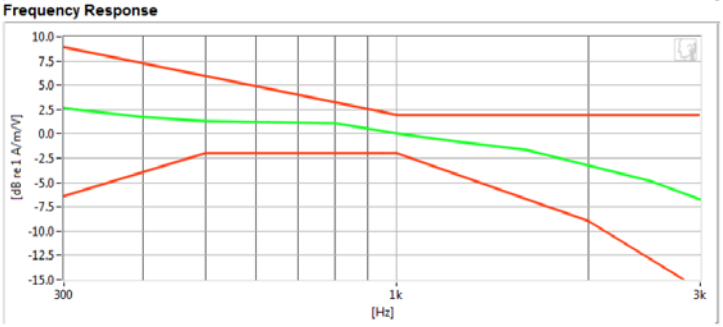
Test Configuration:

- Mode: LTE TDD Band 38
- Bandwidth: 15MHz
- Channel: 37825
- Speech Signal: 3GPP2 Normal Test Signal

Noise Spectrum



Frequency Response



Results

ABM1	1.04 dB	✓	Minimum	-18.0
ABM2	-44.77 dB	✓	Maximum	0.0
SNNR	45.81 dB	✓	Minimum	20.0
Aligned Response - Normal	2 dB	✓	Tolerance curves	Aligned Data

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07/05/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMN960U

Type: Portable Handset
Serial: 44867

Measurement Standard: ANSI C63.19-2011

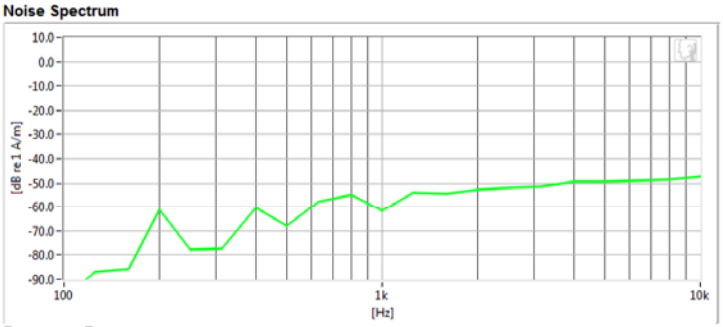
Equipment:

- Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

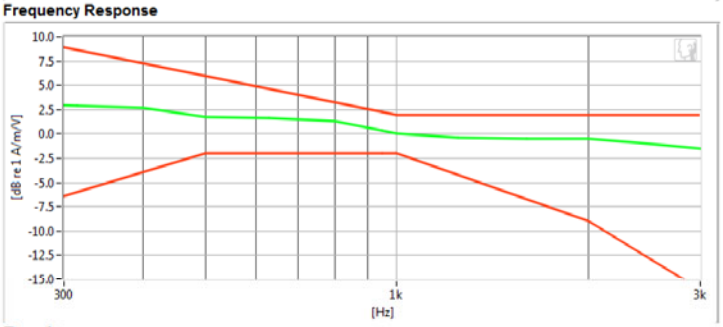
Test Configuration:

- VoIP Application: Google Duo
- Mode: LTE TDD Band 38
- Bandwidth: 15MHz
- Channel: 37825
- Speech Signal: 3GPP2 Normal Test Signal

Noise Spectrum



Frequency Response



Results

ABM1	9.58 dB	✓	Minimum	-18.0
ABM2	-46.06 dB	✓	Maximum	0.0
SNNR	55.64 dB	✓	Minimum	20.0
Aligned Response - Normal	2 dB	✓	Tolerance curves	Aligned Data

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07/04/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMN960U

Type: Portable Handset
Serial: 44867

Measurement Standard: ANSI C63.19-2011 / CTIA HAC Test Plan v3.1

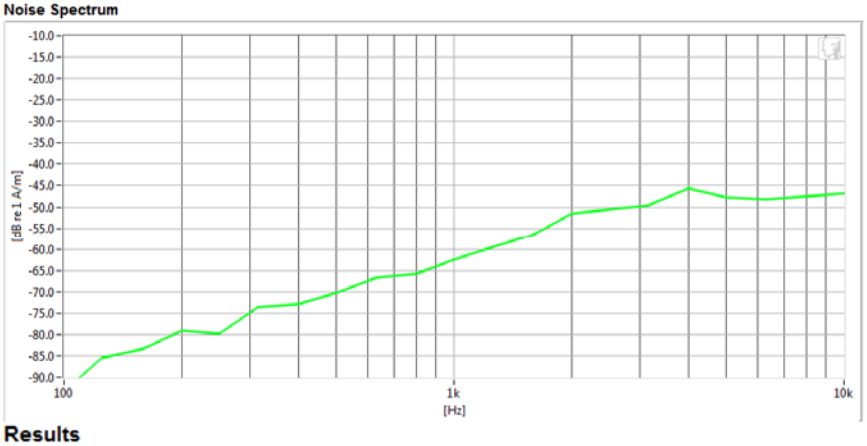
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016

Test Configuration:

- Mode: LTE FDD Band 30
- Bandwidth: 10MHz
- Channel: 27710

Noise Spectrum



Results

ABM1	-6.04 dB	✓	Minimum	-18.0
ABM2	-47.63 dB	✓	Maximum	0.0
SNNR	41.6 dB	✓	Minimum	20.0

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07/04/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMN960U

Type: Portable Handset
Serial: 44867

Measurement Standard: ANSI C63.19-2011 / CTIA HAC Test Plan v3.1

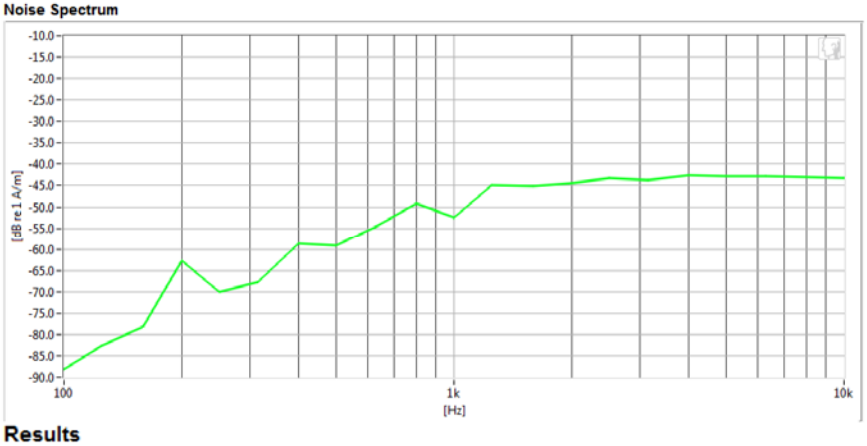
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016

Test Configuration:

- Mode: LTE TDD Band 38
- Bandwidth: 15MHz
- Channel: 37825

Noise Spectrum



Results

ABM1	-5.96 dB	✓	Minimum	-18.0
ABM2	-39.05 dB	✓	Maximum	0.0
SNNR	33.09 dB	✓	Minimum	20.0

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07/05/2018

PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMN960U

Type: Portable Handset
Serial: 44867

Measurement Standard: ANSI C63.19-2011

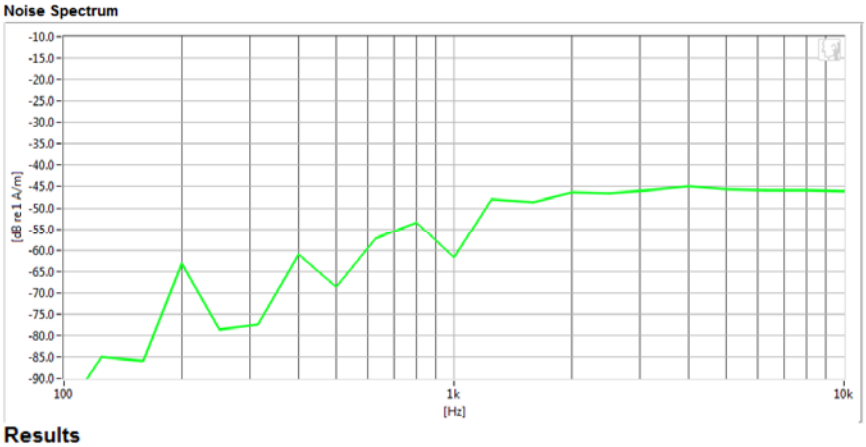
Equipment:

- Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016

Test Configuration:

- VoIP Application: Google Duo
- Mode: LTE TDD Band 38
- Bandwidth: 15MHz
- Channel: 38000

Noise Spectrum



Results

ABM1	2.93 dB	✔	Minimum	-18.0
ABM2	-42.21 dB	✔	Maximum	0.0
SNNR	45.14 dB	✔	Minimum	20.0

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9. CALIBRATION CERTIFICATES

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West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

AXIAL T COIL PROBE

Manufactured by:	TEM CONSULTING
Model No:	AXIAL T COIL PROBE
Serial No:	TEM-1124
Calibration Recall No:	27068

Submitted By:

Customer:	ANDREW HARWELL
Company:	PCTEST ENGINEERING LAB
Address:	6660-B DOBBIN ROAD COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. AXIAL T C TEM C

Upon receipt for Calibration, the instrument was found to be:

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.

12/29/2016

West Caldwell Calibration Laboratories' calibration control system meets the following requirements, ISO 10012-1 MIL STD 45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025

Note: With this Certificate, Report of Calibration is Included.

Approved by:

Calibration Date: 07-Dec-16

FC

Certificate No: 27068 - 3

Felix Christopher (QA Mgr.)

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

ISO/IEC 17025:2005

West Caldwell Calibration Laboratories, Inc.
uncompromised calibration
1575 State Route 96, Victor, NY 14564, U.S.A.

ACCREDITED
Calibration Lab. Cert. # 1533.01

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West Caldwell Calibration Laboratories, Inc.

uncompromised calibration

1575 State Route 96, Victor NY 14564

ISO/IEC 17025: 2005

ACCREDITED

Calibration Lab. Cert. # 1533.01

REPORT OF CALIBRATION

for

TEM Consulting LP Axial T Coil Probe **Model No.: Axial T Coil Probe** **Serial No.: TEM 1124**

Company : PCTEST Engineering Lab. **I. D. No: 80578**

Calibration results:

Probe Sensitivity measured with Helmholtz Coil

Before & after data same: ...X.....

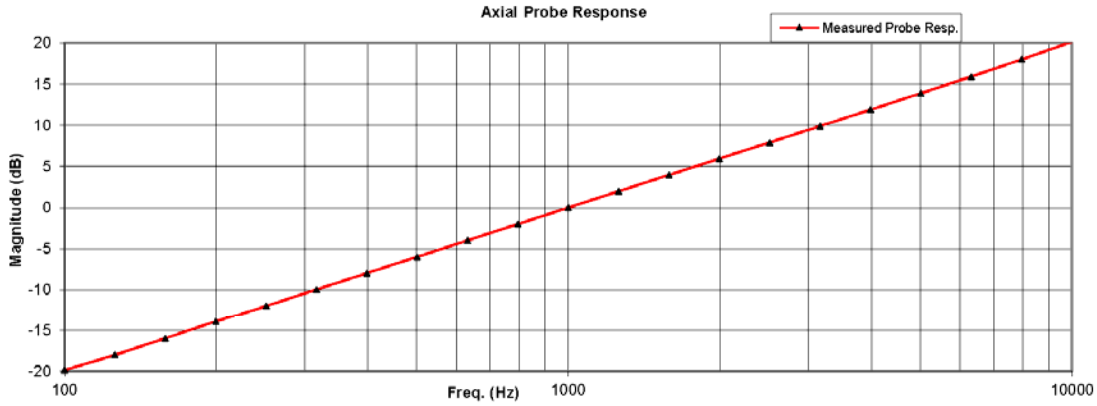
Helmholtz Coil;					
the number of turns on each coil;	10	No.			
the radius of each coil, in meters;	0.204	m	Laboratory Environment:		
the current in the coils, in amperes.;	0.09	A	Ambient Temperature:	20.2	°C
Helmholtz Coil Constant;	7.09	A/m/V	Ambient Humidity:	31.4	% RH
Helmholtz Coil magnetic field;	5.98	A/m	Ambient Pressure:	99.1	kPa
			Calibration Date:	7-Dec-16	
Probe Sensitivity at	1000	Hz.			
was	-60.23	dBV/A/m	Report Number:	27068	-3
	0.974	mV/A/m	Control Number:	27068	
Probe resistance	904	Ohms			

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: 683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure : **Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC**

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 7-Dec-2016 Measurements performed by: FC

Calibrated on WCCL system type 9700 **Felix Christopher**

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Page 1 of 2

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West Caldwell Calibration Laboratories Inc.
1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

for

TEM Consulting LP Axial T Coil Probe **Model No.: Axial T Coil Probe** **Serial No.: TEM 1124**

Company : PCTEST Engineering Lab.

Test	Function		Tolerance		Measured values Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.		dBV/A/m	-60.23		
				dB			
2.0	Probe Level Linearity			6	6.03		
			Ref. (0 dB)	0	0.00		
				-6	-6.03		
				-12	-12.05		
				Hz			
3.0	Probe Frequency Response			100	-19.8		
				126	-18.0		
				158	-16.0		
				200	-13.9		
				251	-12.0		
				316	-9.9		
				398	-8.0		
				501	-6.0		
				631	-4.0		
				794	-2.0		
			Ref. (0 dB)	1000	0.0		
				1259	2.0		
				1585	4.0		
				1995	6.0		
				2512	7.9		
				3162	9.9		
				3981	11.9		
				5012	13.9		
				6310	15.9		
				7943	18.0		
				10000	20.2		

Instruments used for calibration:			Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N 36064102	1-Oct-2016	,287708	1-Oct-2017
HP	34401A	S/N 36102471	1-Oct-2016	,287708	1-Oct-2017
HP	33120A	S/N 36043716	1-Oct-2016	,287708	1-Oct-2017
B&K	2133	S/N 1583254	1-Oct-2016	683/284413-14	1-Oct-2017

Cal. Date: 7-Dec-2016 Tested by: Felix Christopher

Calibrated on WCCL system type 9700

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

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West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

RADIAL T COIL PROBE

Manufactured by:	TEM CONSULTING
Model No:	RADIAL T COIL PROBE
Serial No:	TEM-1130
Calibration Recall No:	27068

Submitted By:

Customer:	ANDREW HARWELL
Company:	PCTEST ENGINEERING LAB
Address:	6660-B DOBBIN ROAD
	COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. RADIAL T TEM C

VASA 12/29/2016

Upon receipt for Calibration, the instrument was found to be:

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.

West Caldwell Calibration Laboratories' calibration control system meets the following requirements, ISO 10012-1 MIL STD 45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025

Note: With this Certificate, Report of Calibration is included.

Approved by:

FC

Calibration Date: 07-Dec-16

Certificate No: 27068 - 2

Felix Christopher (QA Mgr.)
ISO/IEC 17025:2005

QA Doc. #1061 Rev. 2.0 10/1/01

Certificate Page 1 of 1

West Caldwell Calibration Laboratories, Inc.
uncompromised calibration
1575 State Route 96, Victor, NY 14564, U.S.A.

ACCREDITED
Calibration Lab. Cert. # 1533.01

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West Caldwell Calibration Laboratories, Inc.

uncompromised calibration

1575 State Route 96, Victor NY 14564

ISO/IEC 17025: 2005

ACCREDITED

Calibration Lab. Cert. # 1533.01

REPORT OF CALIBRATION

for

TEM Consulting LP Radial T Coil Probe **Model No.: Radial T Coil Probe** **Serial No.: TEM-1130**

Company : PCTEST Engineering Lab. **I. D. No: 80579**

Calibration results:

Probe Sensitivity measured with Helmholtz Coil

Before & after data same: ...X.....

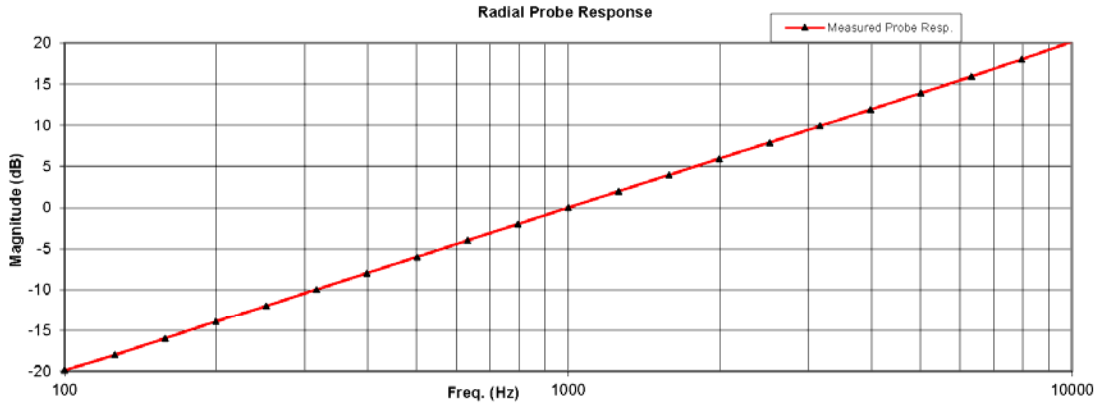
Helmholtz Coil;					
the number of turns on each coil;	10	No.			
the radius of each coil, in meters;	0.204	m	Laboratory Environment:		
the current in the coils, in amperes.;	0.09	A	Ambient Temperature:	20.2	°C
Helmholtz Coil Constant;	7.09	A/m/V	Ambient Humidity:	31.4	% RH
Helmholtz Coil magnetic field;	5.98	A/m	Ambient Pressure:	99.1	kPa
			Calibration Date:	7-Dec-16	
Probe Sensitivity at	1000	Hz.			
was	-60.27	dBV/A/m	Report Number:	27068	-2
	0.969	mV/A/m	Control Number:	27068	
Probe resistance	902	Ohms			

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: 683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure : **Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC**

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 7-Dec-2016 Measurements performed by: FC

Calibrated on WCCL system type 9700 **Felix Christopher**

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

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West Caldwell Calibration Laboratories Inc.
1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

for

TEM Consulting LP Radial T Coil Probe **Model No.: Radial T Coil Probe** **Serial No.: TEM-1130**

Company : PCTEST Engineering Lab.

Test	Function		Tolerance		Measured values Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz.		dBV/A/m	-60.27		
				dB			
2.0	Probe Level Linearity			6	6.03		
			Ref. (0 dB)	0	0.00		
				-6	-6.03		
				-12	-12.06		
				Hz			
3.0	Probe Frequency Response			100	-19.9		
				126	-18.0		
				158	-16.0		
				200	-13.9		
				251	-12.0		
				316	-10.0		
				398	-8.0		
				501	-6.0		
				631	-4.0		
				794	-2.0		
			Ref. (0 dB)	1000	0.0		
				1259	2.0		
				1585	4.0		
				1995	6.0		
				2512	7.9		
				3162	9.9		
				3981	11.9		
				5012	13.9		
				6310	15.9		
				7943	18.0		
				10000	20.2		

Instruments used for calibration:			Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N 36064102	1-Oct-2016	,287708	1-Oct-2017
HP	34401A	S/N 36102471	1-Oct-2016	,287708	1-Oct-2017
HP	33120A	S/N 36043716	1-Oct-2016	,287708	1-Oct-2017
B&K	2133	S/N 1583254	1-Oct-2016	683/284413-14	1-Oct-2017

Cal. Date: 7-Dec-2016 Tested by: Felix Christopher

Calibrated on WCCL system type 9700

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

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10. CONCLUSION

The measurements taken in accordance with the procedures provided in the CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017, indicate that LTE bands 30 and 38 of the wireless communications device complies with the HAC limits specified in the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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